Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/807,636	CHEN ET AL.	
Examiner	Art Unit	
Nam Huynh	2617	

SEARCHED					
Class	Subclass	Date	Examiner		
455	435.1	10/12/2007	NTH		
	435.2				
	435.3				
	455				
	458				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
"				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
See EAST search notes.	10/12/2007	NTH	